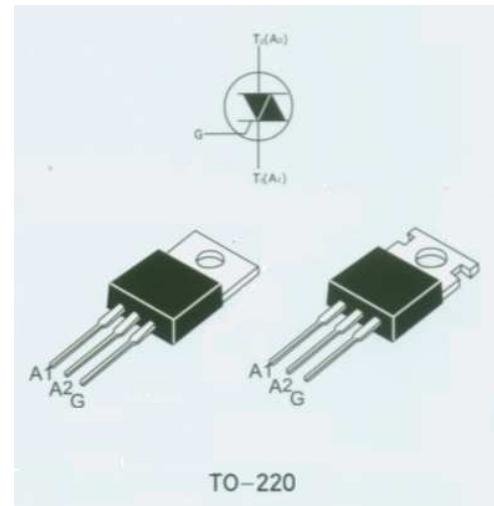


STANDARD
8A TRIACs
MAIN FEATURES

Symbol	Value	Unit
$I_{T(RMS)}$	8	A
$V_{(DRM)}/V_{RRM}$	600 to 800	V
$I_{GT(Q1)}$	5 to 50	mA

GENERAL DESCRIPTION

Passivated triacs in a plastic envelope, Intended for use in applications requiring high bi-directional transient and blocking voltage capability and high thermal cycling performance. Typical applications include motor control, industrial and domestic lighting, heating and static switching.


ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter			Value	Unit
$I_{T(RMS)}$	RMS on-state current (full sine wave)	TO-220AB	$T_c=105^\circ\text{C}$	8	A
		TO-220AB Ins.	$T_c=110^\circ\text{C}$		A
I_{TSM}	Non repetitive surge peak on-state current (full cycle, T_j initial= 25°C)	F=50Hz	$t=20\text{ms}$	65	A
		F=60Hz	$t=16.7\text{ms}$	71	
I^2T	I^2T Value for fusing	$t_p=10\text{ms}$		21	A^2s
di/dt	Critical rate of rise of on-state current $I_G=2 \times I_{GT}$, $t_r \leq 100\text{ns}$	F=120Hz	$T_j=125^\circ\text{C}$	50	$\text{A}/\mu\text{s}$
I_{GM}	Peak gate current	$t_p=20\mu\text{s}$	$T_j=125^\circ\text{C}$	4	A
$P_{G(AV)}$	Average gate power dissipation	$T_j=125^\circ\text{C}$		1	W
T_{stg}	Storage junction temperature range			-40 to+150	$^\circ\text{C}$
T_j	Operating junction temperature range			-40 to+125	

■ STATIC CHARACTERISTICS

 T_j=25°C unless otherwise stated

Symbol	Test Conditions	Quadrant		Value			Unit	
				E	C	B		
I _{GT} ⁽¹⁾	V _D =12V R _L =30Ω	I-II-III	MAX.	10	25	50	mA	
		IV		20	50	100		
V _{GT}		ALL	MAX.	1.5			V	
V _{GD}	V _D =V _{DRM} R _L =3.3KΩ T _j =125°C	ALL	MIN.	0.2			V	
I _H ⁽²⁾	I _T =500mA		MAX.	10	25	50	mA	
I _L	I _G =1.2I _{GT}	I-III-IV	MAX.	20	40	50	mA	
		II		40	80	100		
V _{TM} ⁽²⁾	I _{TM} =11A tp=380μs	T _j =25°C	MAX.	1.6			V	
V _{th} ⁽²⁾	Threshold voltage		T _j =125°C	MAX.	0.85			V
R _d ⁽²⁾	Dynamic resistance		T _j =125°C	MAX.	50			mΩ
I _{DRM} I _{RDM}	V _{DRM} =V _{RRM}	T _j =25°C	MAX.	100			μA	
		T _j =125°C		1			mA	

■ DYNAMIC CHARACTERISTICS

Symbol	Test Condition		E	C	B	Unit	
dV/dt ⁽²⁾	V _D =67% V _{DRM} gate open	T _j =125°C	MIN.	100	200	400	V/μs
(dI/dt) _c ⁽²⁾	(dI/dt) _c =3.5A/ms	T _j =125°C	MIN.	5	5	10	V/μs

Note1: minimum I_{GT} is guaranteed at 5% of I_{GT} max.

Note2: for both polarities of A2 referenced to A1.

■ THERMAL RESISTANCES

Symbol	Parameter		Value	Unit
R _{th(j-l)}	Junction to case (AC)	TO-220AB	1.6	°C/W
		TO-220AB Insulated	2.5	
R _{th(j-a)}	Junction to ambient	TO-220AB	60	°C/W
		TO-220AB Insulated		

PERFORMANCE CURVES

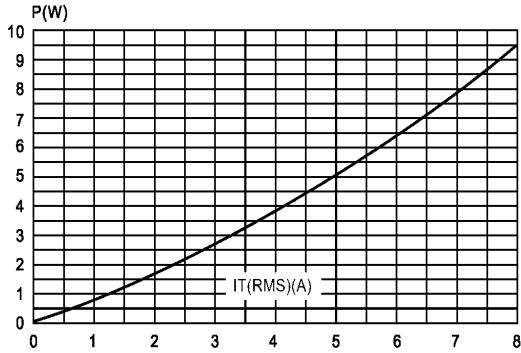


Fig. 1. Maximum power dissipation versus RMS on-state current (full cycle)

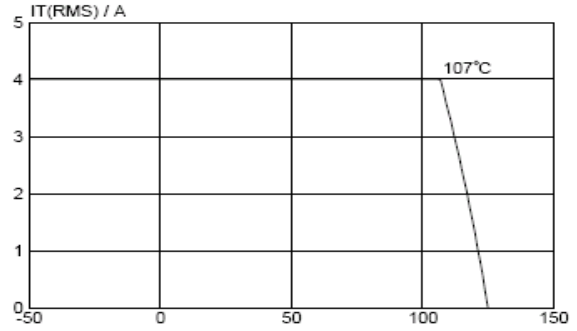


Fig. 4. RMS on-state current versus ambient temperature (full cycle)

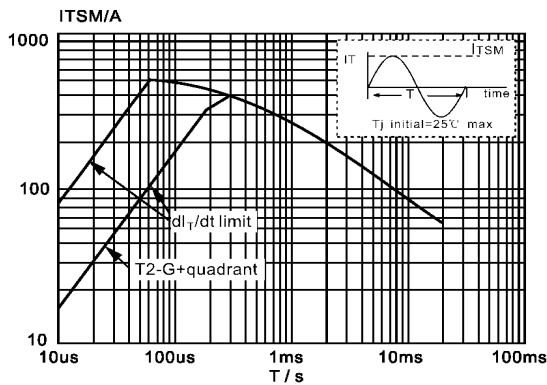


Fig. 2. Maximum permissible non-repetitive peak on-state current I_{TSM} versus pulse width t_p , for sinusoidal currents, $t_p \leq 20ms$

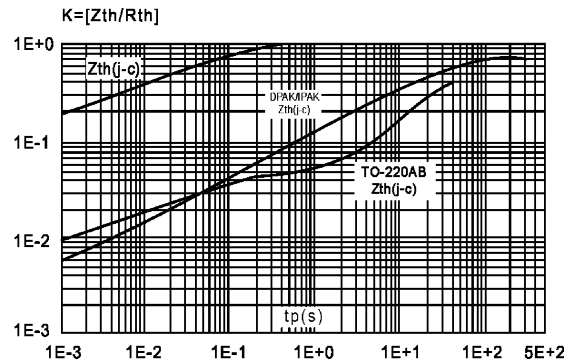


Fig. 5. Relative variation of thermal impedance versus pulse duration

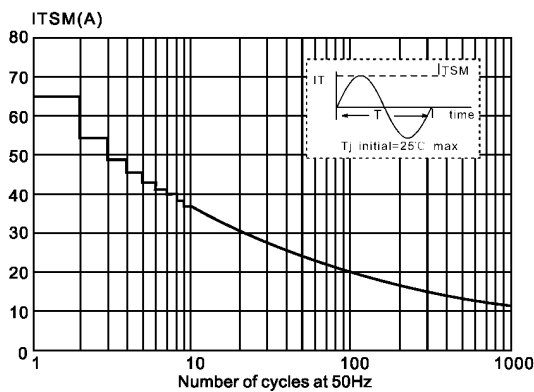


Fig. 3. Maximum permissible non-repetitive peak on-state current I_{TSM} versus number of cycles, for sinusoidal currents, $f=50Hz$

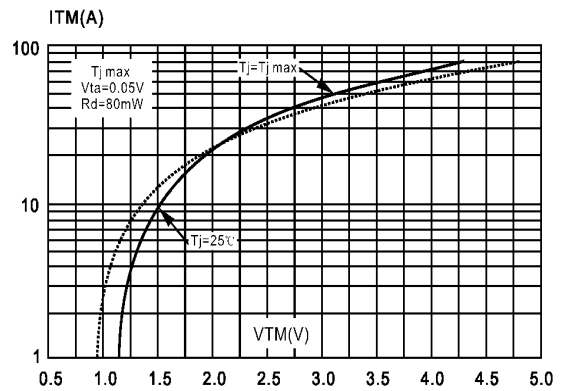


Fig. 6. On-state characteristics (maximum values),

PERFORMANCE CURVES

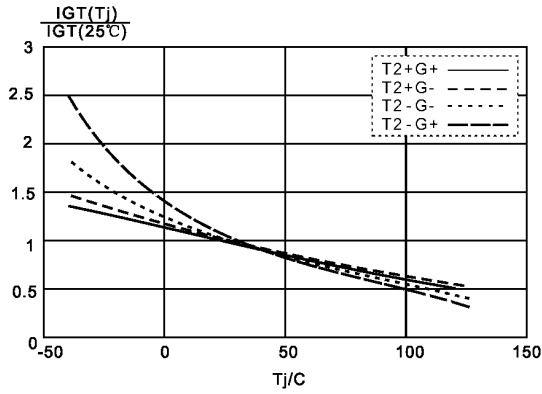


Fig. 7. Normalized gate trigger current $I_{GT}(T_j)/I_{GT}(25^\circ\text{C})$, versus junction temperature T_j

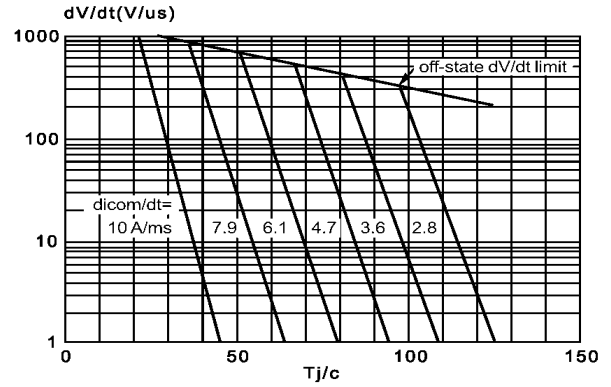


Fig. 10. Typical commutation dV/dt versus junction temperature, parameter commutation dI_T/dt is below the value on the appropriate curve for pre-commutation dI_T/dt

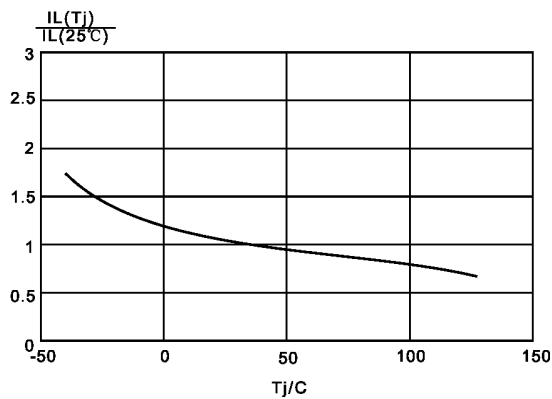


Fig. 8. Normalized latching current $I_L(T_j)/I_L(25^\circ\text{C})$, versus junction temperature T_j

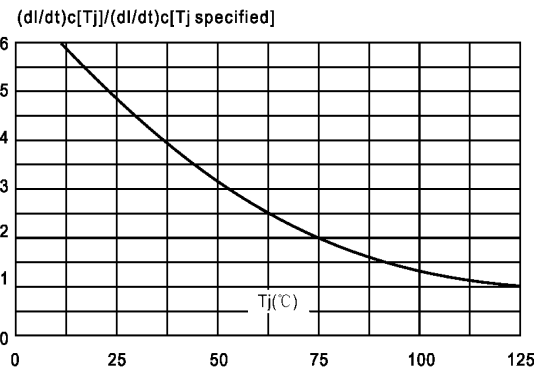


Fig. 11. Relative variation of critical rate of decrease of main current versus junction temperature T_j

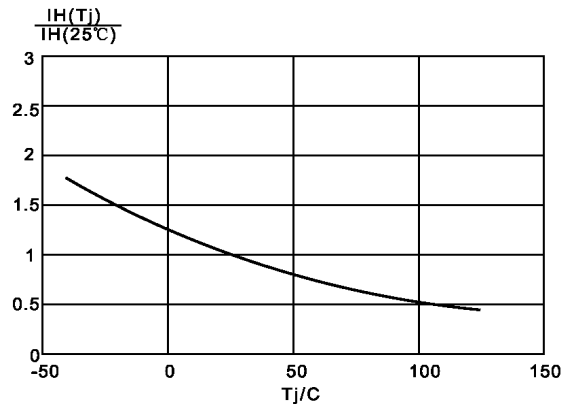


Fig. 9. Normalized holding current $I_H(T_j)/I_H(25^\circ\text{C})$, versus junction temperature T_j

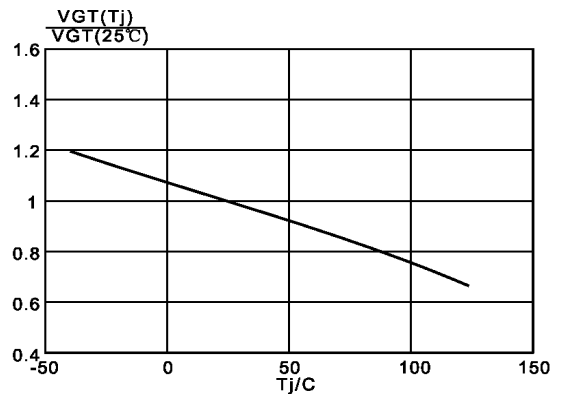
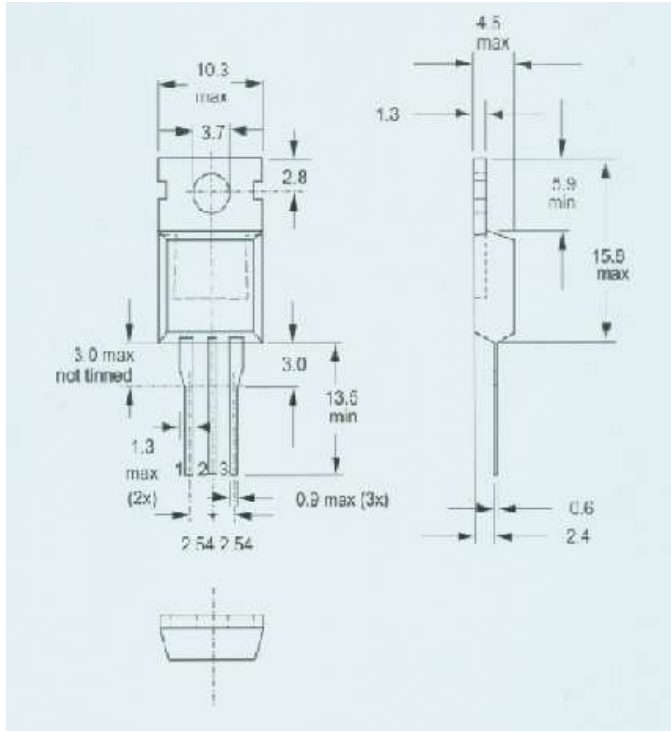


Fig. 12. Normalized gate trigger voltage $V_{GT}(T_j)/V_{GT}(25^\circ\text{C})$, versus junction temperature T_j

PACKAGE MECHANICAL DATA

TO-220



TO-220

